

### KSC3569

## **High Speed Switching Application**

- Low Collector Saturation Voltage
- Specified of Reverse Biased SOA With Inductive Loads



## **NPN Epitaxial Silicon Transistor**

### 1.Base 2.Collector 3.Emitter

### Absolute Maximum Ratings T<sub>C</sub>=25°C unless otherwise noted

Symbol	Parameter	Value	Units
V <sub>CBO</sub>	Collector-Base Voltage	500	V
V <sub>CEO</sub>	Collector-Emitter Voltage	400	V
V <sub>EBO</sub>	Emitter-Base Voltage	7	V
I <sub>C</sub>	Collector Current (DC)	2	Α
I <sub>CP</sub>	*Collector Current (Pulse)	4	Α
I <sub>B</sub>	Base Current	1	Α
P <sub>C</sub>	Collector Dissipation (T <sub>C</sub> =25°C)	15	W
TJ	Junction Temperature	150	°C
T <sub>STG</sub>	Storage Temperature	- 55 ~ 150	°C

<sup>\*</sup> PW≤350μs, Duty Cycle≤10%

## $\textbf{Electrical Characteristics} \ \, \textbf{T}_{\text{C}} = 25^{\circ} \text{C unless otherwise noted}$

Symbol	Parameter	Test Condition	Min.	Max.	Units
V <sub>CEO</sub> (sus)	Collector-Emitter Sustaining Voltage	$I_C = 0.5A$ , $I_{B1} = 0.1A$ , $L = 1mH$	400		V
V <sub>CEX</sub> (sus)1	Collector-Emitter Sustaining Voltage	$I_C = 0.5A$ , $I_{B1} = -I_{B2} = 0.1A$ $T_a = 125$ °C, $L = 180\mu$ H, Clamped	450		V
V <sub>CEX</sub> (sus)2	Collector-Emitter Sustaining Voltage	$I_C = 1A$ , $I_{B1} = -I_{B2} = 0.2A$ , $T_a = 125$ °C, $L = 180\mu H$ , Clamped	400		V
I <sub>CBO</sub>	Collector Cut-off Current	$V_{CB} = 400V, I_{E} = 0$		10	μΑ
I <sub>CER</sub>	Collector Cut-off Current	$V_{CE} = 400V, R_{BE} = 51\Omega$ @ $T_{C} = 125^{\circ}C$		1	mA
I <sub>CEX1</sub>	Collector Cut-off Current	$V_{CE} = 400V, V_{BE} (off) = -5V$		10	μΑ
I <sub>CEX2</sub>	Collector Cut-off Current	$V_{CE} = 400V, V_{BE} \text{ (off)} = -5V @ $ $T_{C} = 125^{\circ}\text{C}$		1	mA
I <sub>EBO</sub>	Emitter Cut-off Current	$V_{BE} = 5V, I_{C} = 0$		10	μΑ
h <sub>FE1</sub> h <sub>FE2</sub>	* DC Current Gain	$V_{CE} = 5V, I_{C} = 0.1A$ $V_{CE} = 5V, I_{C} = 0.5A$	20 10	80	
V <sub>CE</sub> (sat)	* Collector-Emitter Saturation Voltage	$I_C = 0.5A, I_B = 0.1A$		1	V
V <sub>BE</sub> (sat)	* Base-Emitter Saturation Voltage	$I_C = 0.5A, I_B = 0.1A$	-	1.2	V
t <sub>ON</sub>	Turn ON Time	$V_{CC} = 150V, I_{C} = 0.5A$		1	μs
t <sub>STG</sub>	Storage Time	$I_{B1} = -I_{B2} = 0.1A$		2.5	μs
t <sub>F</sub>	Fall Time	$R_L = 300\Omega$		1	μs

<sup>\*</sup> Pulse Test: PW≤350μs, Duty Cycle≤2% Pulsed

### **h**<sub>FE</sub> Classification

Classification	R	0	Y
h <sub>FE1</sub>	20 ~ 40	30 ~ 60	40 ~ 80

# **Typical Characteristics**

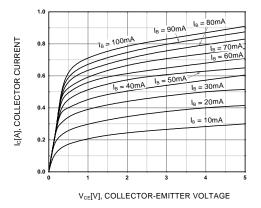


Figure 1. Static Characteristic

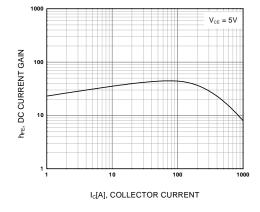


Figure 2. DC current Gain

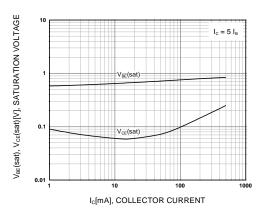


Figure 3. Base-Emitter Saturation Voltage Collector-Emitter Saturation Voltage

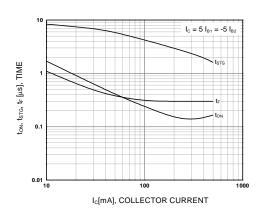


Figure 4. Switching Time

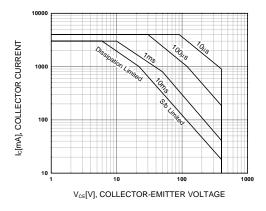


Figure 5. Safe Operating Area

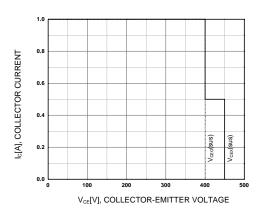
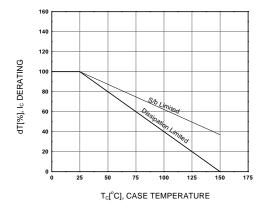


Figure 6. Reverse Bias Safe Operating Area

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# **Typical Characteristics** (Continued)



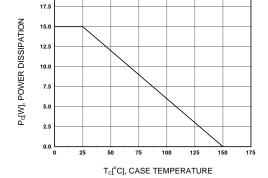
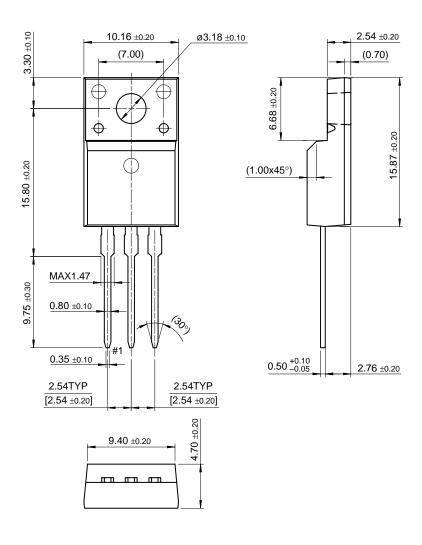


Figure 7. Derating Curve of Safe Operating Area

Figure 8. Power Derating

# **Package Demensions**

# TO-220F



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